

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/524,098	LEE ET AL.
	Examiner	Art Unit
	Quynh H. Nguyen	2614

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
379	207.08 207.16 211.03 211.04 374.03 375.01	9/18/07	QN
455	433 466	9/18/07	QN
Interference searched history printout		9/18/07	QN